

**Search Notes**

Application/Control No.

10/521,460

Examiner

Scott Bushey

Applicant(s)/Patent under  
Reexamination

CHIBA, MITSURU

Art Unit

1724

**SEARCHED**

Class	Subclass	Date	Examiner
261	121.1,124, 122.1, Dig. 65		
128	200.11		
128	200.13	3/29/2006	CSB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search and Text Search	3/29/2006	CSB